

<b>Notice of References Cited</b>	Application/Control No. 10/775,425		Applicant(s)/Patent Under Reexamination RIET, EGBERT JAN VAN	
	Examiner Frank S. Tsay		Art Unit 3672	Page 1 of 1

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*	C	US-6,176,323	01-2001	Weirich et al.	175/40
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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